Se	arch N	otes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/727,594	DELBREIL ET AL.
Examiner	Art Unit
JOHN J. LEE	2618

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	403 561 50.11	5/10/2007	J.L
709	224	5/10/2007	J.L

INTERFERENCE SEARCHED		
Subclass	Date	Examiner
	WHO # 12	10 1
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East	5/10/09	FL